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Technical Compliance

No. ACS-E21402

The following product has been tested by us with the listed standards and found in compliance with the council EMC directive 2014/30/EU. It is demonstrative for the compliance with this EMC Directive.

Applicant : Shenzhen Century Cloud Core Technologies Limited
 F1-F5, B1 Complex Building, Gangtou Industrial Park, Yabian
 Community, Shajing Town, Baoan District, Shenzhen

Product : SERVER

Model No. : j1-11

Test Standards:

EN 55032: 2015+A11: 2020 (Class A) EN 55032: 2015	Electromagnetic compatibility of multimedia equipment - Emission requirements	
EN IEC 61000-3-2: 2019	Electromagnetic compatibility(EMC) Part 3-2:Limits-Limits for harmonic current emissions(equipment input current ≤16A per phase)	
EN 61000-3-3: 2013+A1: 2019	Electromagnetic compatibility(EMC) Part 3-3:Limits-Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current ≤16A per phase and not subject to conditional connection	
EN 55035: 2017 EN 55035: 2017+A11: 2020	Electromagnetic compatibility of multimedia equipment — Immunity requirements	
	IEC 61000-4-2: 2008	Electrostatic Discharge
	IEC 61000-4-3: 2006+A1: 2007+A2: 2010	RF Field Strength Susceptibility
	IEC 61000-4-4: 2012	Electrical Fast Transients
	IEC 61000-4-5: 2014+A1: 2017	Surge
	IEC 61000-4-6: 2013	Continuous Conducted disturbance
	IEC 61000-4-8: 2009	Magnetic Field Immunity
	IEC 61000-4-11: 2004+A1: 2017	Dips / Voltage Interruption Variation



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 EMC 部門報告專用章
 Stamp only for EMC Dept. Report
 Signature: Bensun Chen

Bensun Chen
 Manager
 Date: Dec.15, 2021

The technical compliance is based on a single evaluation of one sample of above mentioned product. It does not imply an assessment of the whole production and does not permit the use of the test lab. logo.